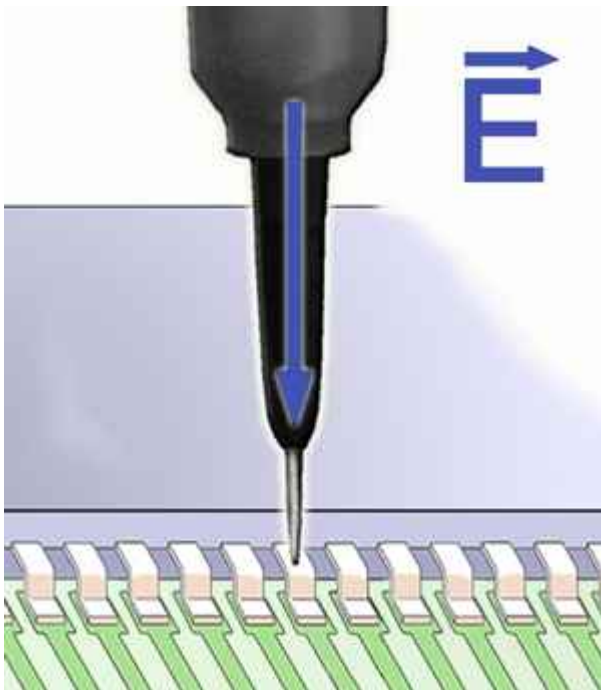


### Short description

The ES 08-h E field source is a test probe to determine the sensibility of a IC pin or a line. For measurements the probe must be in contact with a pin / conducting path and, because of its changing interference pulse intensities from the EFT/burst generator, the sensitivity of the pin / conducting path can be detected. Inside the field source the interference pulse is coupled capacitively on the tip. Thus, useful signals are not loaded.

The field source is powered by an EFT/ burst generator. The generator ist connected to the 4.4 kV, high-voltage resistant SMB plug of the field source via a high voltage cable ( HV SMB 1 m or SMB-BNC 1 m).

### Measuring principles



Application with ES 08D

